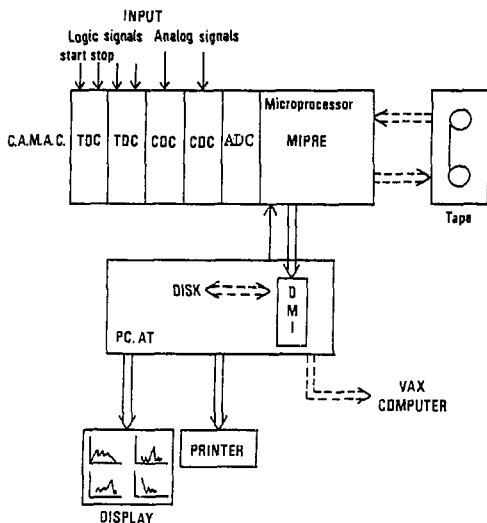


This data acquisition system is fast and well adapted to time of flight experiments. It includes one CAMAC power supply, 2 TDC's, 2 CDC's and ADC's, a power



full pre-programmed microprocessor and a modified PC AT with the software for data analysis. Fig. 1 shows a schematic diagram of the system. Data can be transferred in the list mode from the MIPRE to a 6250 BPI tape in order to be able to make sophisticated subsequent analysis, event by event, if necessary. There is also a possibility to connect the PC to a VAX computer through an Ethernet link.

Fig. 1: Diagram of the data acquisition system.

For 10^4 start pulse/second, a time range of 100 μ sec externally set on the TDC (this time range depends on the maximum time of flight) and 100 stop events per start event about $5 \cdot 10^7$ counts per second can be analysed and stored in memory.

In the coincidence mode, 1000 start events with 10 stop events (per second) on one TDC allow to record 10 spectra (2 single TDC spectra, 2 multistop distribution spectra and 6 correlated spectra corresponding to coincidence windows).

A new time digital converter for secondary ion time of flight mass spectrometry has been developed and tested at the Institut. This TDC is used in the present data acquisition system. It combines the advantages of measuring the exact time event by event and the number of secondary ions described by the primary process (fission fragment, pulsed keV ion gun or even laser shot). The pulse height response of microchannel plates (MCP)

is proportional to the number of ions hitting simultaneously the detector. This has been verified with secondary electrons emitted from a surface bombarded by

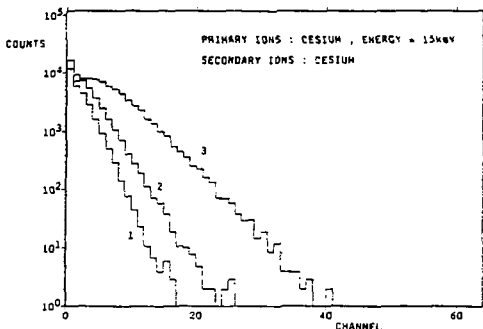


Fig. 2: Pulse height distributions of the stop detectors under secondary Cs^+ ion impacts. Three different values of the primary ion beam intensities have been used: 1 (10 Primary Ions per pulse), 2 (20 P.I./pulse), 3 (40 P.I./pulse).

keV ions and bent by a magnetic field either to a silicon detector or to a MCP detector. A linear response has been measured for both detectors [5]. Fig. 2 shows distributions of pulse height responses from a MCP detector bombarded by different numbers of incident cesium ions arriving at the same instant on the detector. A pulsed Cs ion gun was used to induce desorption of Cs^+ from a CsI target. An increasing number of primary ions per pulse was used to generate an increasing number of Cs^+ secondary ions. With a normal multistop TDC [6] only the time is measured between the start pulse and the stop pulses whatever the number of secondary ions hitting the detector.

This means that only one count is added in the "histogram memory" at the corresponding time. In the new version of the apparatus a number proportional to the area of the distributions is added in the memory at the corresponding time. The digital (see Fig. 2) conversion is made within the dead time of the TDC (around 20 nsec) and 6 bits are used for the conversion (possibility of 8 bits if necessary).

Two spectra are shown in Fig. 3A-B. Fig. 3A shows the spectrum measured with the normal multistop TDC [6]. Fig. 3B shows the spectrum obtained during the same recording time with the new TDC. It is seen that intensities of H^+ and Cs^+ ions are enhanced because of multi ion impacts. The Cs^+ peak is increased by 2.5. This electronic module will be extremely useful in the

future not only to improve the analytical measurements but also for desorption mechanism studies.

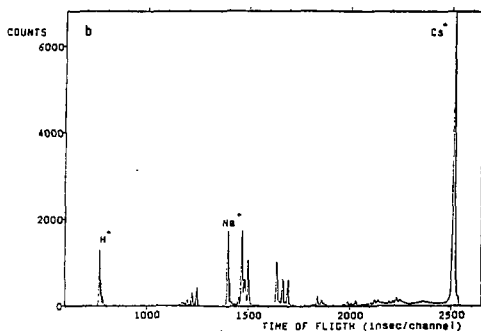
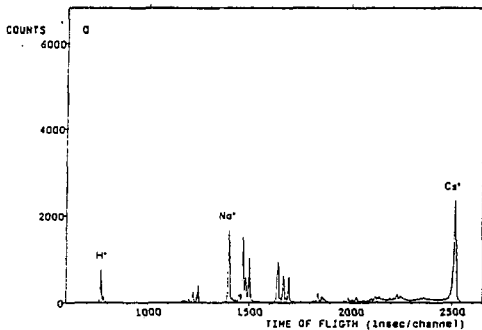


Figure 3
Secondary ion
spectra showing
the response of
the new TDC
(same time of
measurement)
A. normal mul-
tistop TDC
B. new TDC.

We have very much appreciated enthusiastic discussions with A. Richard and R. Sellem from the Electronic Division. We are very grateful to C. Cuzon and A. Richard who have electronically conceived the new multistop time and charge digital converter (MTCDC).

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